Searcn Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/603,538	DAYAN ET AL.	
Examiner	Art Unit	
James K. Trujillo	2116	

	SEARCHED		
Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
See at	tached	3/14/2007	JKT

SEARCH NO (INCLUDING SEARCH)
	DATE	EXMR
EAST (USPAT, US-PGPUB, EPO, JPO, DERWENT, IBM_TDB), see attached; NPL: IEEE; Inventor Search/DP	4/5/2006	JKT
updated; text search in 713, 709	3/15/2007	JKT